

## Refine Search

### Search Results -

Terms	Documents
semiconductor and (nanoscale same roughness)	0

**Database:**

US Pre-Grant Publication Full-Text Database  
 US Patents Full-Text Database  
 US OCR Full-Text Database  
 EPO Abstracts Database  
 JPO Abstracts Database  
 Derwent World Patents Index  
 IBM Technical Disclosure Bulletins

**Search:**

L7	<input type="button" value="Refine Search"/>	
<input type="button" value="Recall Text"/>	<input type="button" value="Clear"/>	<input type="button" value="Interrupt"/>

### Search History

DATE: Wednesday, February 16, 2005 [Printable Copy](#) [Create Case](#)

Set Name Query  
side by side

Hit Count Set Name  
result set

<i>DB=JPAB; PLUR=YES; OP=ADJ</i>		
<u>L7</u> semiconductor and (nanoscale same roughness)	0	<u>L7</u>
<i>DB=EPAB; PLUR=YES; OP=ADJ</i>		
<u>L6</u> semiconductor and (nanoscale same roughness)	0	<u>L6</u>
<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L5</u> semiconductor and (nanoscale same roughness)	24	<u>L5</u>
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L4</u> semiconductor and (nanoscale same roughness)	29	<u>L4</u>
<i>DB=TDBD; PLUR=YES; OP=ADJ</i>		
<u>L3</u> semiconductor and (nanoscale same roughness)	1	<u>L3</u>
<i>DB=DWPI; PLUR=YES; OP=ADJ</i>		
<u>L2</u> semiconductor and (nanoscale same roughness)	1	<u>L2</u>
<u>L1</u> 6417060.pn.	1	<u>L1</u>

END OF SEARCH HISTORY